


<b>Search Notes</b> 	<b>Application/Control No.</b> 10813212	<b>Applicant(s)/Patent Under Reexamination</b> QUMEI, IYAD
	<b>Examiner</b> Chen, Shin-Hon	<b>Art Unit</b> 2131

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
USPAT, PGPUB, DERWENT, JPO, EPO (BRS search - see search history)	6/13/07	S.C.

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
713	191, 193	4/15/11	S.C.
380	281,282,283, 285	4/15/11	S.C.
455	418,419	4/15/11	S.C.

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